

Energy transfer from Ce³⁺ to Tb³⁺ in low quartz and amorphous SiO₂ hosts

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Abstract. Low quartz and amorphous Ce³⁺-Tb³⁺ co-activated SiO₂ phosphors were synthesized by a solution combustion method using urea as a fuel and sol-gel respectively. The objective of this study was to compare the efficiency of energy transfer from Ce³⁺ to Tb³⁺ in low quartz and amorphous SiO₂ hosts. The phosphors were annealed in a reducing atmosphere of 4% H₂/96% Ar mixture at an elevated temperature of 1000°C for 2 hours. This was meant to reduce incidental presence of Ce⁴⁺ (non-luminescent) to a fully homogeneous distribution of Ce³⁺ ions in the silica matrix. As confirmed by X-ray diffraction (XRD) data, SiO₂ was produced as either low quartz or in the amorphous phase. The photoluminescence (PL) data showed that green emission of Tb³⁺ at 543 nm was sensitized by Ce³⁺, i.e. there was energy transfer from Ce³⁺ to Tb³⁺ resulting in an improvement of the green line emission due to the ⁵D₄→⁷F₅ transitions of Tb³⁺ ions. A possible mechanism of UV down-converted green emission due to energy transfer from Ce³⁺ to Tb³⁺ is discussed.

1. Introduction

Silica is widely used in so many fields such as medium layer and silicon-based photoelectron material for its excellent chemical stability, thermal stability as well as interfacial combination with silicon semiconductor. However, taking into consideration that SiO₂ can either be generated in the crystalline or amorphous form, it has then stimulated a long history of experimental and theoretical investigations. On that note, SiO₂ doped with metal ions can also be studied as a luminescence material. The rare earth or transition metal ions [1-4] are often used as activator ions to enhance the luminescent properties of silica for their unique electronic structures. For example, Tb³⁺ ions due to their extensive use as materials for fabricating various optical re-radiators and cathodoluminescent screens when incorporated into glasses have developed great interest for many researchers [5,6]. However, the problem of enhancing the light output of Tb³⁺ - containing glasses upon UV excitation still remains unresolved. The reason is that the light output of these materials is limited by the occurrence of intense absorption bands in the high-frequency range due to $4f^8 \rightarrow 4f^7(^8S_{7/2})5d^1(T_2)$ and $4f^7(^8S_{7/2})5d^1(E)$ inter configurational transitions [7] and a relatively low efficiency of excitation transfer from the luminescence sensitizers. In this work we synthesized low quartz and amorphous SiO₂ hosts doped with Ce³⁺ and Tb³⁺ ions to attempt to solve the problem through the comparative study on their structures and spectroscopic properties. In particular, we focus the attention in the performance of the energy transfer from Ce³⁺ to Tb³⁺ in low quartz and the amorphous phases..

2. Experimental procedure

Nano sized pure SiO₂, singly doped SiO₂ with Ce and Tb, and SiO₂ co-doped samples with (Ce³⁺/Tb³⁺) were prepared by a solution combustion method as described in reference [8]. Silicic acid (SiO₂·nH₂O) and ammonium nitrate (NH₄NO₃) were used as the starting materials, urea (CH₄N₂O) was used as fuel and both cerium and terbium nitrates were used as dopant precursors. On the other hand, the same set of samples were prepared by using a sol-gel method where the starting materials were as follow: tetraethylorthosilicate (Si(OC₂H₅)₄, TEOS), ethanol (ETOH), distilled water and nitric acid

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(0.15 M HNO₃, as a catalyst). All the samples prepared were annealed in a reducing atmosphere of a 4%H₂/96%Ar mixture at an elevated temperature of 1000°C for 2 hours. The phase purity and crystallinity of the powder samples was characterized by X-ray powder diffraction (XRD). XRD measurements were carried out with a Bruker D8 Advanced powder diffractometer with Cu-K α radiation ($\lambda = 1.5418 \text{ \AA}$) in the 2θ range from 10° to 80°. The morphology of the prepared nanoparticles was analyzed by scanning electron microscopy (SEM) using a Shimadzu model ZU SSX-550 Superscan. The photoluminescence (PL) properties of the powder phosphors were characterized using a Cary Eclipse fluorescence spectrophotometer.

3. Results and discussion

3.1. X-ray diffraction

The XRD patterns of the pure SiO₂ and singly doped SiO₂:xmol% Tb³⁺ ($x = 1, 4$), SiO₂:2mol%Ce³⁺ and co-doped SiO₂:2mol%Ce³⁺, xmol%Tb³⁺ ($x = 1, 4$) powders prepared with the combustion method are shown in figure 1. The undoped SiO₂ and singly doped SiO₂: xmol%Tb³⁺ ($x = 1, 4$) patterns show only a broad peak around $2\theta = 23.6^\circ$. On the other hand, a singly doped SiO₂:2mol%Ce³⁺ co-doped samples show a broad peak and some small signatures emanating from low quartz silica. The observed peaks were assigned by comparing the JCPDS database file no 86-1565, which is the characteristics diffraction pattern of the low quartz's phase of a SiO₂ glassy matrix. Figure 2 shows the XRD patterns of the sol-gel derived pure SiO₂ and singly doped SiO₂:xmol% Tb³⁺ ($x = 1, 4$), SiO₂:2mol%Ce³⁺ and co-doped SiO₂:2mol%Ce³⁺, xmol%Tb³⁺ ($x = 1, 4$) powder phosphors. The observed broad peak from a pure SiO₂ and a singly doped SiO₂:xmol% Tb³⁺ ($x = 1, 4$) at $2\theta = 23.6^\circ$ is similar to the XRD pattern shown in Figure 1. The only exception here is that pure SiO₂ derived from sol-gel is completely amorphous when compared with pure SiO₂ derived from the combustion of which has a peak shift towards lower angle suggesting that there is a uniform strain present since the preparation temperature for combustion is higher that of sol-gel route. Singly doped SiO₂:xmol% Tb³⁺ ($x = 1, 4$) have a broad peak respectively, and there is a shift towards a lower angle. For SiO₂:2mol%Ce³⁺ and co-doped SiO₂:2mol%Ce³⁺, xmol%Tb³⁺ ($x = 1, 4$) the XRD data confirmed that all the powder samples crystallize and match well with the JCPDS standard (Fig. 1) in a low quartz after heat treatment.

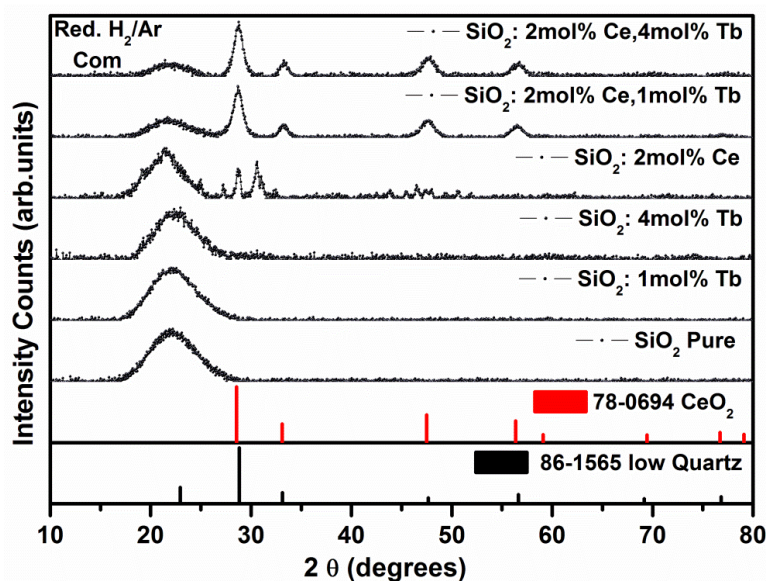


Figure 1. Room temperature XRD patterns of (as cast) pure SiO₂ and a singly doped SiO₂:x mol% Tb³⁺ ($x = 1, 4$), SiO₂:2mol%Ce³⁺ and co-doped SiO₂:2mol%Ce³⁺, xmol%Tb³⁺ ($x = 1, 4$) from combustion derived route.

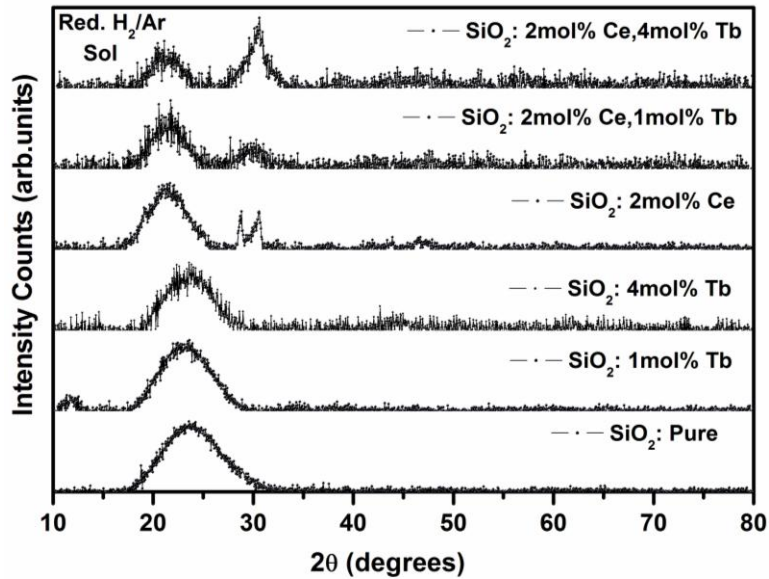


Figure 2. Room temperature XRD patterns of (as cast) pure SiO_2 and a singly doped $\text{SiO}_2:x \text{ mol}\% \text{Tb}^{3+}$ ($x = 1, 4$), $\text{SiO}_2:2 \text{ mol}\% \text{Ce}^{3+}$ and co-doped $\text{SiO}_2:2 \text{ mol}\% \text{Ce}^{3+}, x \text{ mol}\% \text{Tb}^{3+}$ ($x = 1, 4$) from Sol-gel derived route.

3.2. Scanning electron microscopy (SEM)

The SEM images in figure 3 show the general morphology of the (a) $\text{SiO}_2:2 \text{ mol}\% \text{Ce}$ and $\text{SiO}_2:2 \text{ mol}\% \text{Ce}, 1 \text{ mol}\% \text{Tb}$ samples, respectively. The SEM image in figure 3 (a) shows the agglomerated $\text{SiO}_2:\text{Ce}$ with small particles appearing circular confirming spherical shapes. However, in figure 3 (b) the particles are relatively smaller than shown in (a), which suggest that the Tb incorporation interferes with the crystal growth [9].

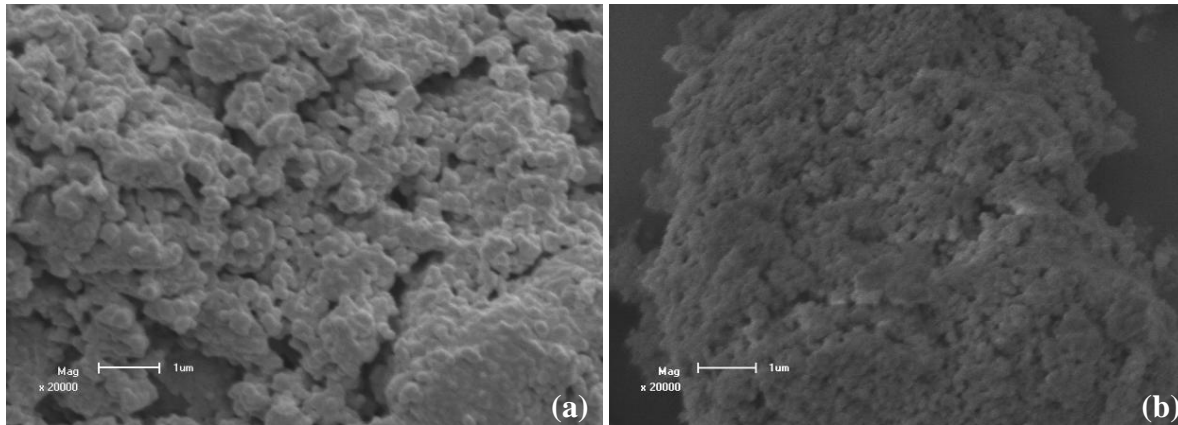


Figure 3. SEM images of the (a) $\text{SiO}_2:2 \text{ mol}\% \text{Ce}$ and (b) $\text{SiO}_2:2 \text{ mol}\% \text{Ce}, 1 \text{ mol}\% \text{Tb}$ samples

3.3. Photoluminescence studies

Figure 4 exhibit the PL emission spectra of the reduced singly doped $\text{SiO}_2:2 \text{ mol}\% \text{Ce}^{3+}$ and $\text{SiO}_2:1 \text{ mol}\% \text{Tb}^{3+}$ respectively. The emission from singly doped $\text{SiO}_2:2 \text{ mol}\% \text{Ce}^{3+}$ at 402 nm is consistent with the 400 nm emission ascribed to Ce^{3+} ions as reported by Kroon et al [10]. On the other hand, PL emission corresponding to Tb^{3+} characteristics show sharp emission peaks from upper-laying levels, i.e., $^5\text{D}_4 \rightarrow ^7\text{F}_{6,5,4,3}$ at 488, 543, 585 and 620 nm, respectively. These peaks match well with emissions from Tb^{3+} ions into nanocrystalline silica, confirming their incorporation into the

system, according to the previous results obtained by the authors using sol-gel derived SiO₂ doped with Tb³⁺ [11].

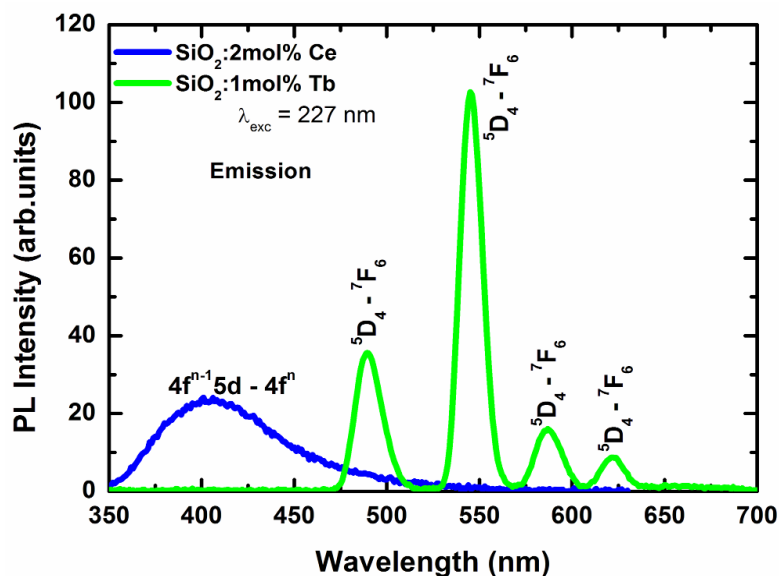


Figure 4. PL emission spectra SiO₂:2 mol% Ce and SiO₂:1mol% Tb ($\lambda_{exc} = 227$ nm).

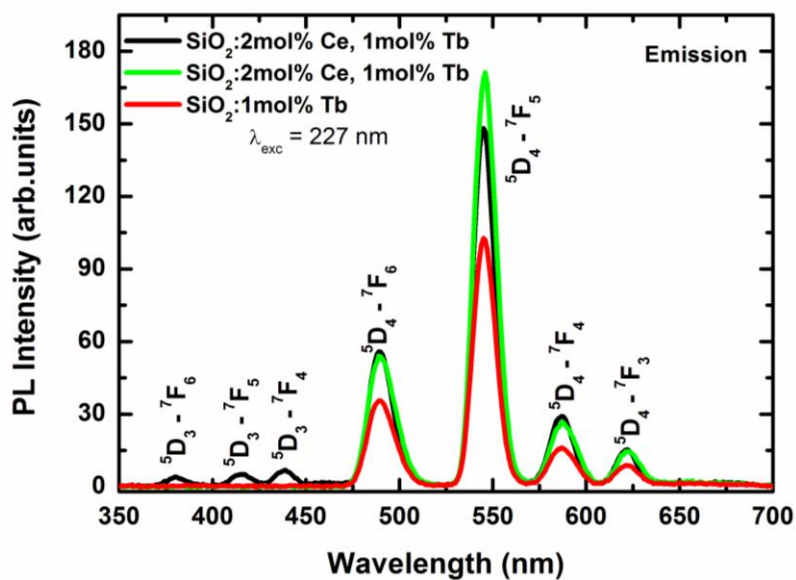


Figure 5. PL emission spectra of SiO₂ singly doped with 1 mol% Tb³⁺ and co-doped with 2Ce³⁺ and 1Tb³⁺ in mol% under excitation at 227 nm. Corresponding transitions are indicated (Green: sol-gel, Black: combustion).

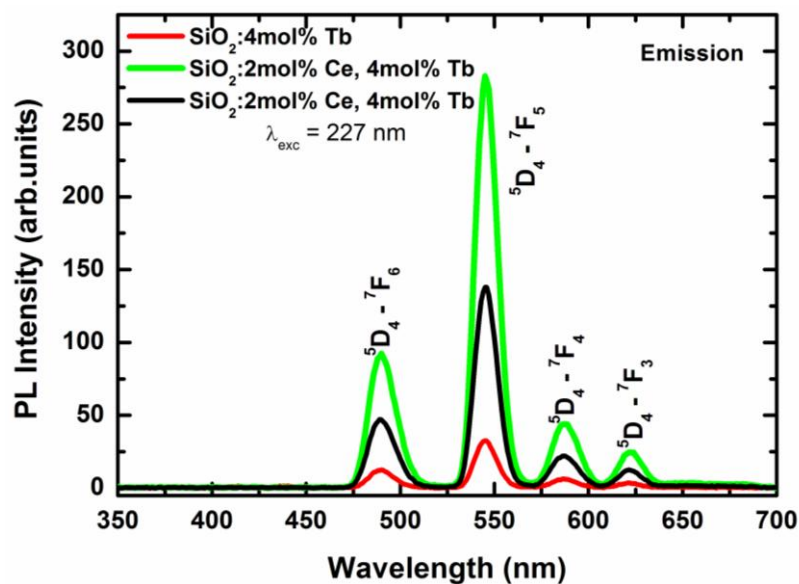


Figure 6. PL emission spectra of SiO₂ singly doped 4 mol% Tb³⁺ and co-doped with 2Ce³⁺ and 4Tb³⁺ in mol% under excitation at 227 nm. Corresponding transitions are indicated (Green: sol-gel, Black: combustion).

Figure 5 & 6 respectively, mainly focuses on the samples obtained as low quartz after some heat treatment in a reduced atmosphere with 2 mol% of Ce³⁺ ions while varying the concentration of Tb³⁺ ions. In particular, samples exhibiting low quartz were derived from the combustion route while that derived from the sol-gel route became crystalline after heat treatment was applied. Therefore, the rest of the paper is design to compare the performance of Ce³⁺ and Tb³⁺ into low quartz and amorphous SiO₂ hosts through energy transfer (ET) efficiency studies. In figure 5 the PL emission ($\lambda_{exc} = 227$ nm) spectra of the co-doped SiO₂:Ce³⁺, Tb³⁺ and singly doped SiO₂:Tb³⁺ are compared. It can be noted that all characteristic emission peaks of Tb³⁺ ions from $^5D_3 \rightarrow ^7F_J$ ($J = 6,5,4$) to $^5D_4 \rightarrow ^7F_J$ ($J=6,5,4,3$) are well pronounced from the low quartz matrix, confirming their incorporation into nanocrystals as shown in section 3.2. However, the intensity of the emission at 543 nm in SiO₂:Ce³⁺,Tb³⁺ derived from nanocrystals silica due to some heat treatment was much bigger than that of a singly doped SiO₂:Tb³⁺. This excitation wavelength 227 nm is attributed to the absorption spectrum of the Ce(IV) valence states as a series of excitonic excitations from orbitals of atoms that surround tetravalent Ce into a silica matrix [12]. Therefore, taking a look at a broad Ce emission (350 – 500 nm) in Figure 4 in comparison to the co-doped systems represented in Figure 5 & 6 respectively, we can conclude that the energy transfer from Ce³⁺ to Tb³⁺ took place. Furthermore, the intensity of the Ce³⁺ as seen from Figure 4 decreases completely in a co-doped SiO₂: Ce,Tb meanwhile increases the Tb³⁺ emission when the Tb³⁺ content is enlarged i.e (from 1 to 4 mol% Tb³⁺). As a result, the energy transfer rate from Ce³⁺ to Tb³⁺ is the best in nanocrystalline SiO₂ host instead of amorphous.

4. Conclusions

SiO₂, SiO₂: Ce, SiO₂: Tb and SiO₂: Ce,Tb powders were successfully synthesized through combustion and sol-gel routes and later reduced in a mixture of 4% H₂/96% Ar at 1000°C for 2 hr. The structural and spectroscopic study in Ce³⁺ and Tb³⁺ single and co-doped SiO₂ has been carried out. The XRD data confirmed that the samples crystallized after heat treatment in a reduced atmosphere. The SEM images showed the agglomerated platelet-like particles of SiO₂: Ce with encrusted small spheroidal particles. Due to the incorporation of Ce³⁺ and Tb³⁺ ions in the silica hosts, energy transfer from Ce³⁺ to Tb³⁺ ions was observed. The transfer rate was more efficient in the low quartz than the amorphous host. Thus, the maximum energy transfer was observed from the sample co-doped with 2 mol% Ce³⁺ and 4 mol% Tb³⁺.

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